

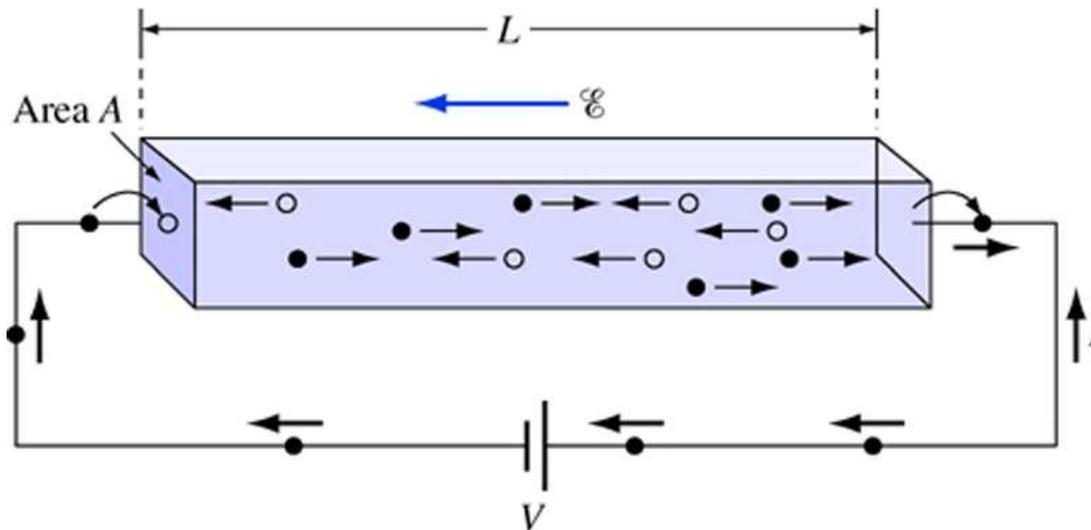
Moving Charge Carriers

Electron mobility

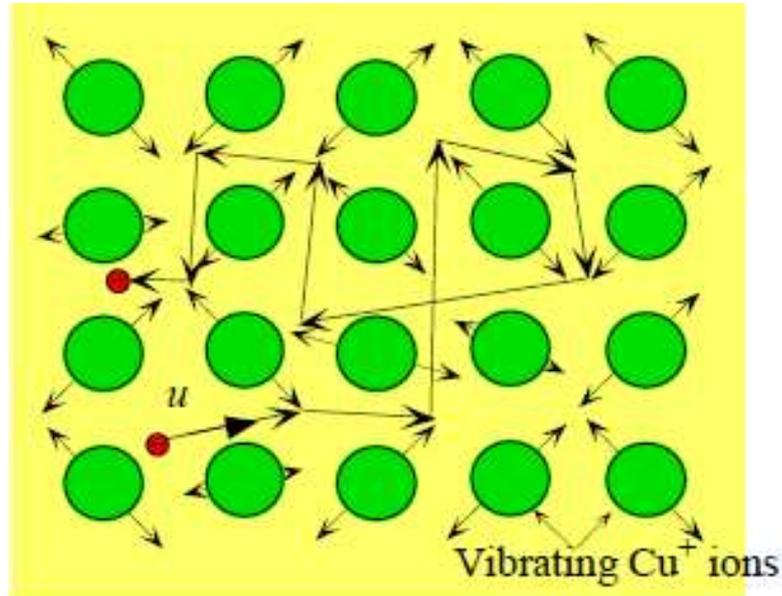
- In solid-state physics, the **electron mobility** characterizes how quickly an electron can move through a metal or semiconductor, when pulled by an electric field.
- In semiconductors, there is an analogous quantity for holes, called **hole mobility**.
- The term **carrier mobility** refers in general to both electron and hole mobility in semiconductors.

How carrier moves...

- When a voltage is applied to a sample, an electric field is induced. This forces a movement in both the electrons and the holes.



Electron movement



In the absence of any electric field, An electron moves about randomly in a metal, obeying the laws of Brownian motion. That is, they just jitter around.

Brownian motion

- At finite temperature, the kinetic energy of a sample is equal to its thermal energy.

- $\frac{1}{2} m v^2 = \frac{1}{2} K_B T$

where

K is Boltzmann constant at $T=300\text{K}$

$$K_B T = 25 \text{ meV}$$

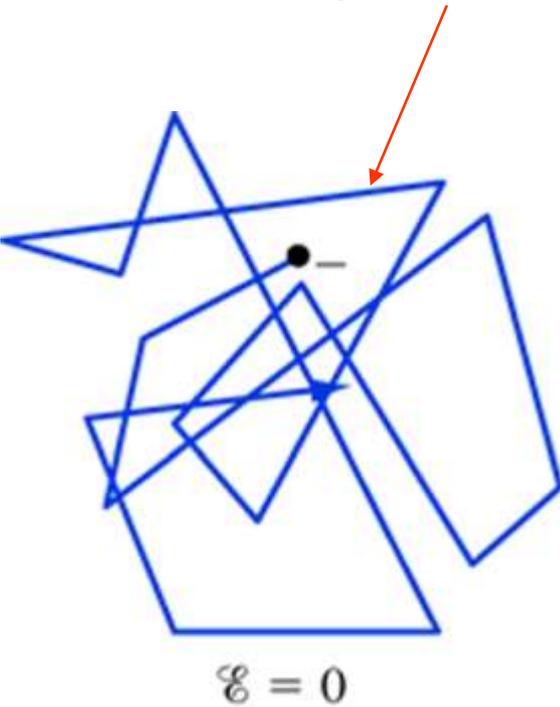
- This is very small amount of energy, but if we multiply with an electron's mass, we get...

$$v = 10^7 \text{ cm/sec approx}$$

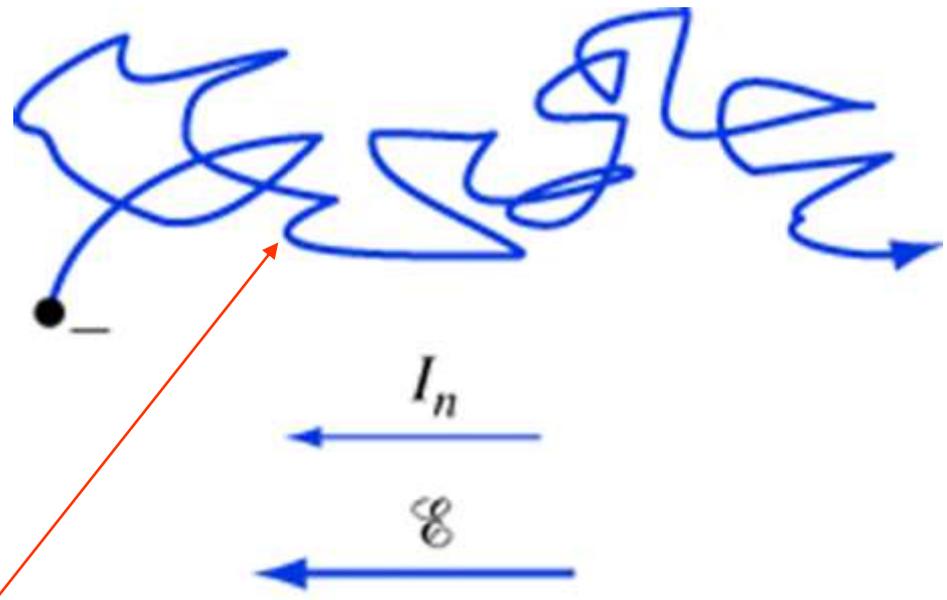
The motion of an electron in a crystal. The electron changes direction randomly whenever it makes a collision.

- (a) Under no applied field there is no net progress in any particular direction.
- (b) When a field is applied, the electron tends to drift in some particular direction. A trajectory such as this would be found only under very high fields.

Only Thermal Motion

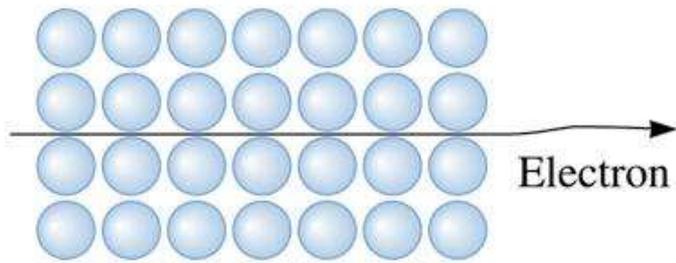


(a)

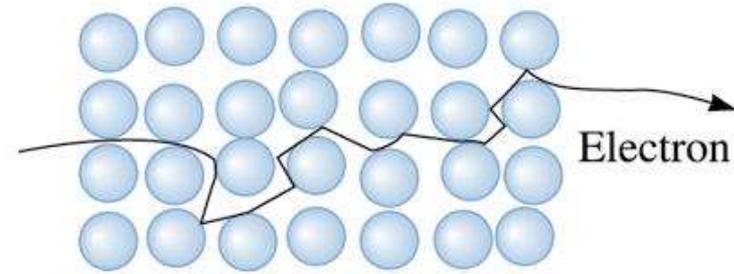


(b)

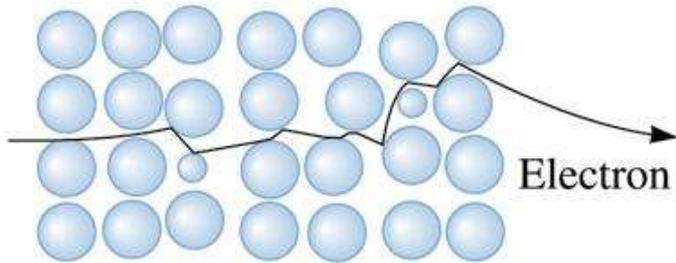
Thermal + Drift motion.



(a)



(b)



(c)

Movement of an electron through

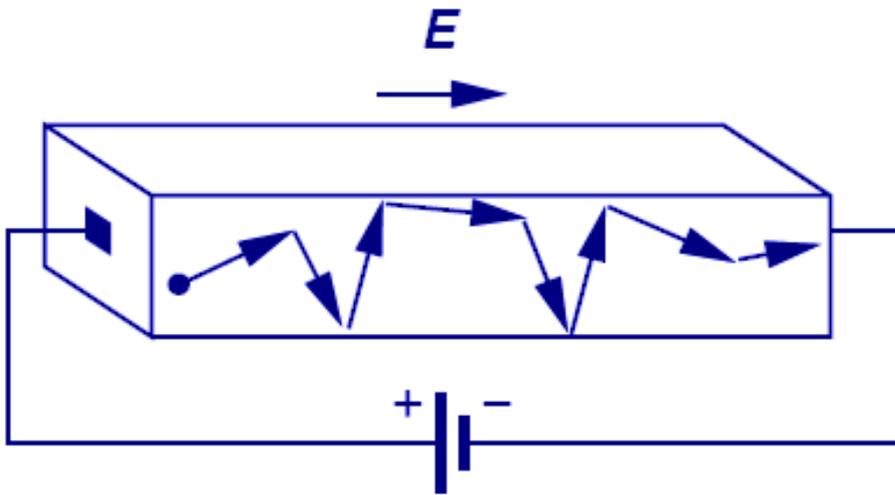
(a) a perfect crystal

(b) a crystal heated to a high temperature

(c) a crystal containing atomic level defects. Scattering of the electrons reduces the mobility and conductivity.

Carrier Drift

- The process in which charged particles move because of an electric field is called *drift*.
- Charged particles within a semiconductor move with an average velocity proportional to the electric field.
 - The proportionality constant is the carrier *mobility*.



$$\text{Hole velocity } \vec{v}_h = \mu_p \vec{E}$$

$$\text{Electron velocity } \vec{v}_e = -\mu_n \vec{E}$$

Notation:

$\mu_p \equiv$ hole mobility ($\text{cm}^2/\text{V}\cdot\text{s}$)

$\mu_n \equiv$ electron mobility ($\text{cm}^2/\text{V}\cdot\text{s}$)

μ_p VS μ_n

- For Si:

$$\mu_p = 480 \text{ cm}^2/\text{v.s}$$

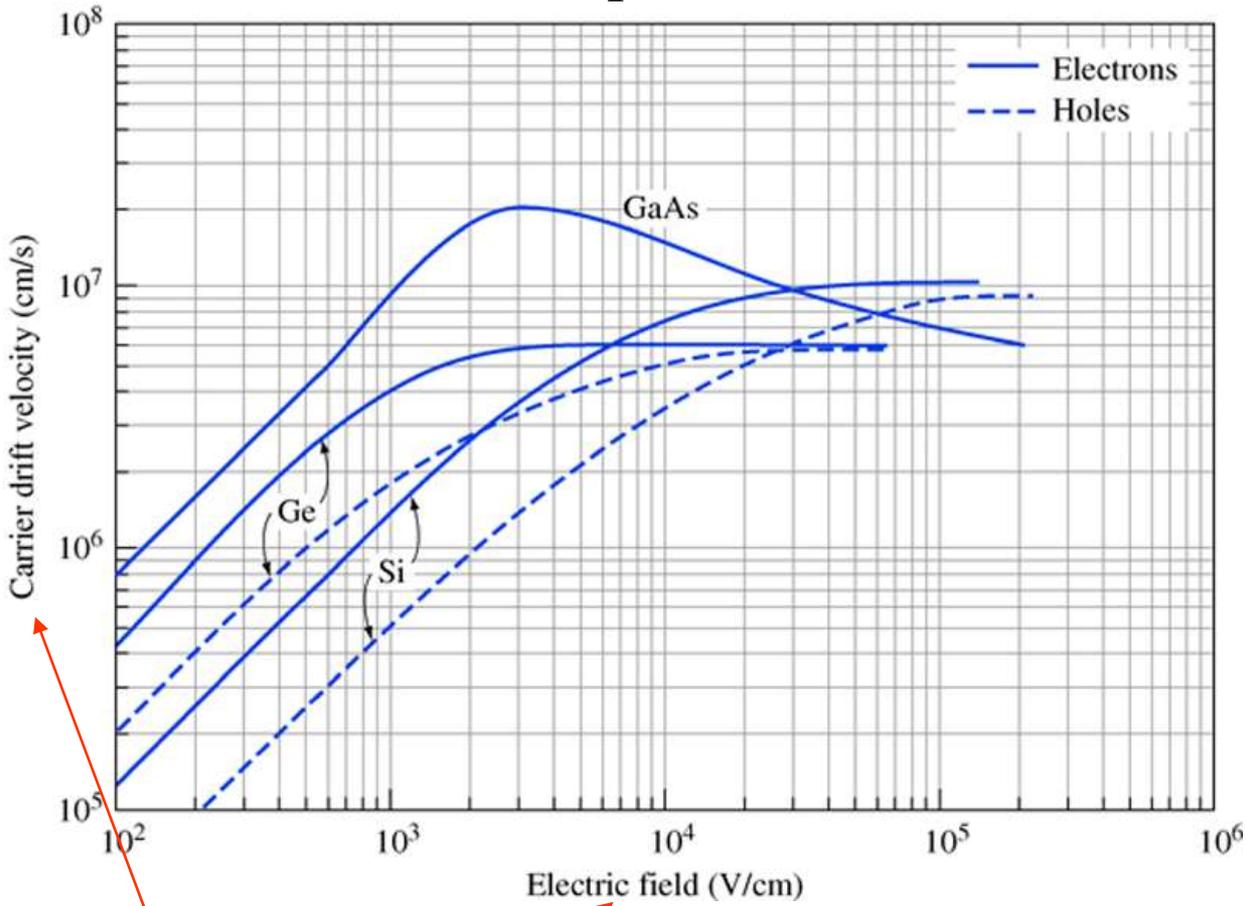
$$\mu_n = 1350 \text{ cm}^2/\text{v.s}$$

So.....

$$\mu_n = 2.5 \mu_p$$

The experimentally measured dependence of the **drift velocity** on the applied field.

At room temperature

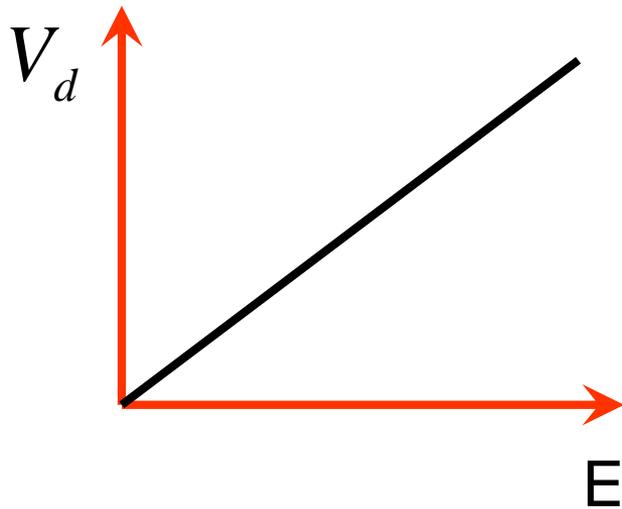


$$v_{\text{drift}} = \mu E$$

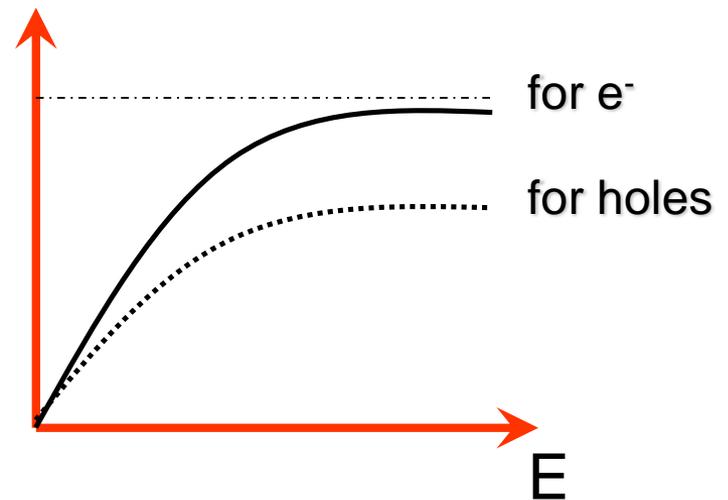
Saturated Drift Velocities

$$V_d = \mu E$$

So one can make a carrier go as fast as we like just by increasing the electric field!!!



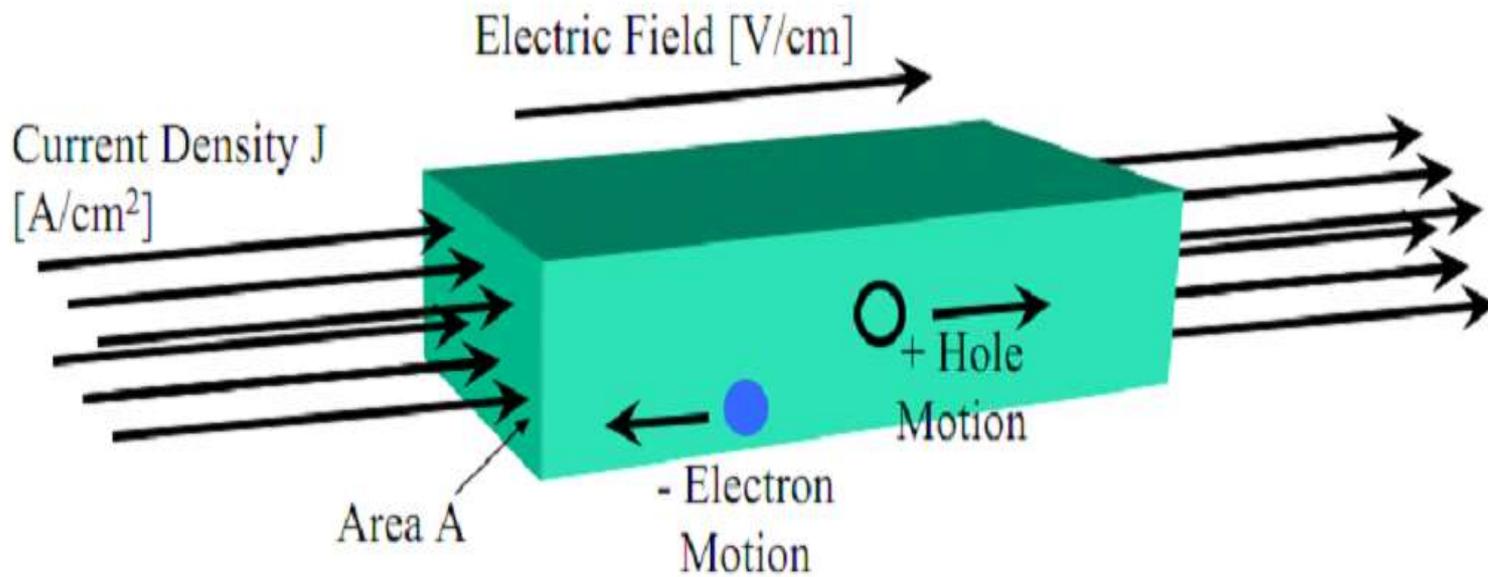
(a) Implication of above eqn.



(b) Actual drift velocity

Saturated Drift Velocities

- The equation of $V_d = \mu \cdot E$ does not imply that V_d increases linearly with applied field E .
- V_d increases linearly for low values of E and then it saturates at some value of V_d which is close V_{th} at higher values of E .
- Any further increase in E after saturation point does not increase V_d , instead it warms up the crystal.



Given current density J ($I=J \times \text{Area}$) flowing in a semiconductor block with face area A under the influence of electric field E , the component of J due to drift of carriers is:

$$J_{p| \text{Drift}} = q p v_d \quad \text{and} \quad J_{n| \text{Drift}} = q n v_d$$



Hole Drift current density



Electron Drift current density

Drift Current Equations

For undoped or intrinsic semiconductor ;

For electron

$$J_n = nqE\mu_n$$

drift
current
for
electrons

number
of free
electrons
per unit
volume

mobility
of
electron

For hole

$$J_p = pqE\mu_p$$

drift
current
for holes

number
of free
holes per
unit
volume

mobility
of holes

Conductivity and Resistivity

$$J_{p,drift} = q p \mu_p E \quad J_{n,drift} = -q n (-\mu_n E)$$

$$J_{tot,drift} = J_{p,drift} + J_{n,drift} = q p \mu_p E + q n \mu_n E$$

$$J_{tot,drift} = q(p\mu_p + n\mu_n)E \equiv \sigma E$$

- The **conductivity** of a semiconductor is $\sigma \equiv q p \mu_p + q n \mu_n$
 - Unit: 1/ohm-cm
- The **resistivity** of a semiconductor is $\rho \equiv \frac{1}{\sigma}$
 - Unit: ohm-cm

Diffusion current

- Diffusion : Nature attempts to reduce concentration gaps to zero.
e.g. spreading of drop of ink in water.
- In semiconductors, this “flow of carriers” from one region of higher concentration to lower concentration results in a “diffusion current”.

Diffusion Current

- Diffusion current density = charge \times carrier flux

$$J_n^{diff} = qD_n \frac{dn}{dx}$$

$$J_p^{diff} = -qD_p \frac{dp}{dx}$$

Where D_p is the diffusion constant. For holes and electrons diffusing in intrinsic Si, typical values would be $D_p=12\text{cm}^2/\text{sec}$ and $D_n=34\text{cm}^2/\text{sec}$.

❖ Total Current Density

When both an electric field and a concentration gradient is present, the total current density becomes;

$$J_n = q\mu_n nE + qD_n \frac{dn}{dx}$$

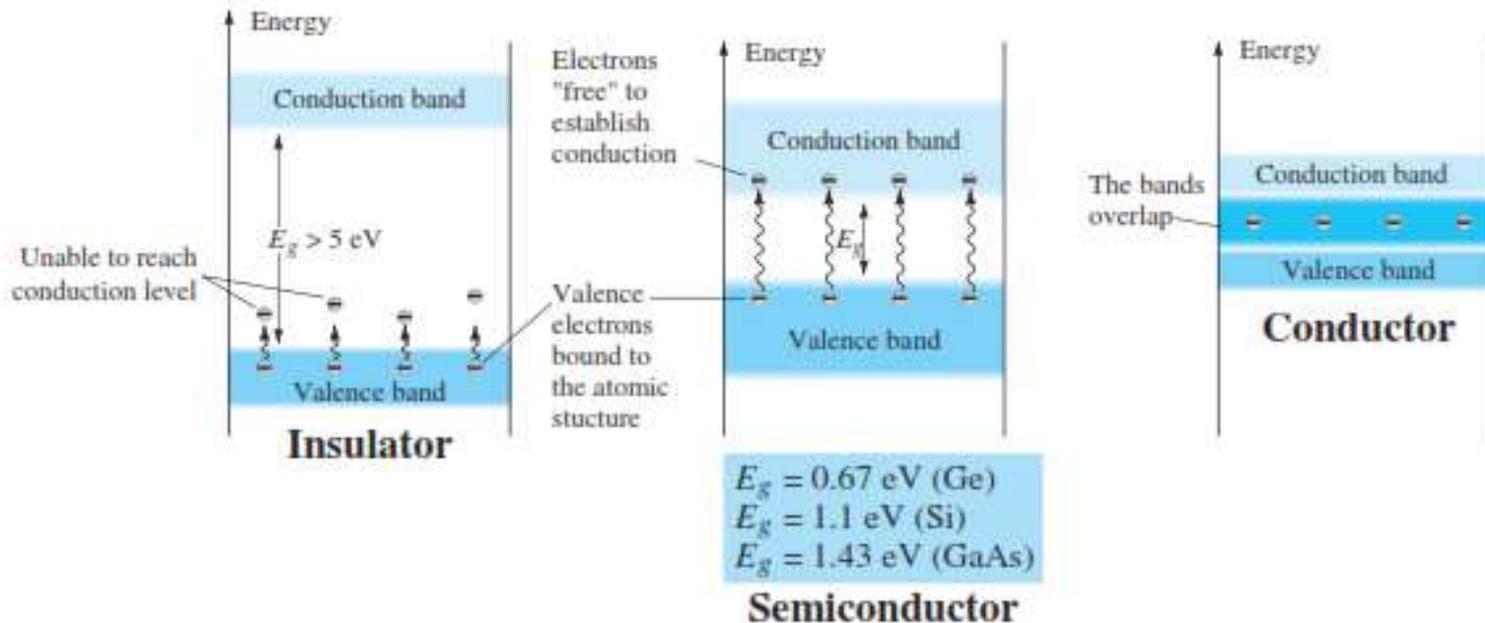
$$J_p = q\mu_p pE - qD_p \frac{dp}{dx}$$

$$J_{total} = J_n + J_p$$

Diffusion current versus drift current

Diffusion current	Drift current
<p>(WHEN).</p> <p>Diffusion current occurs even though there isn't an electric field applied to the semiconductor .</p>	<p>Drift current depends on the electric field applied on the p-n junction diode.</p>
<p>(WHY)</p> <p>It depends on constants D_p and D_n, and $+q$ and $-q$, for holes and electrons respectively but it is independent of permittivity.</p>	<p>It depends upon permittivity.</p>
<p>(WHERE)</p> <p>Direction of the diffusion current depends on the change in the carrier concentrations.</p>	<p>Direction of the drift current depends on the polarity of the applied field.</p>

Energy Levels



The farther an electron is from the nucleus, the higher is the energy state, and any electron that has left its parent atom has a higher energy state than any electron in the atomic structure.